

Ming Yan

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Google Scholar: <https://scholar.google.com/citations?user=Nye2GwkAAAAJ&hl=zh-CN>

EDUCATION

- **College of Intelligence and Computing, Tianjin University** Tianjin, China
Ph.D. Candidate in Software Engineering *September 2021 - Present*
Advisor: Prof. Junjie Chen
- **College of Intelligence and Computing, Tianjin University** Tianjin, China
Master of Software Engineering *September 2018 - July 2021*
Senior Thesis: Numerical Bugs Detection for Deep Learning Program via Gradient Search
Advisors: Prof. Zan Wang, Prof. Junjie Chen
- **College of Intelligence and Computing, Tianjin University** Tianjin, China
Bachelor of Software Engineering *September 2014 - July 2018*
Advisor: Prof. Zan Wang

RESEARCH INTERESTS

- Quality assurance of infrastructures in DL systems, such as DL libraries, and DL compilers. Besides, I am also interested in operating system testing and chip design testing.

INTERNSHIP

- **Huawei Noah's Ark Lab** Beijing, China
Research Intern *April 2021 - May 2022*
- **China Automotive Technology & Research Center Co. Ltd** Tianjin, China
Research Intern *January 2018 - June 2018*

PUBLICATIONS

“ † ” : refers to the first student author and “ * ” : refers to the corresponding author.

1. [IST'23] **Stratified random sampling for neural network test input selection. (CCF-B)**
Zhuo Wu, Zan Wang, Junjie Chen, Hanmo You, Ming Yan, Lanjun Wang*.
In: Information and Software Technology, 2023, pages to appear.
2. [Journal of Software'23] **Test Case Selection for Deep Neural Networks via Data Mutation. (CCF-B)**
Xuejie Cao, Junjie Chen*, Ming Yan, Hanmo You, Zhuo Wu, Zan Wang.
In: Journal of Software, 2023, pages to appear (in Chinese).
3. [JSEP'23] **Revisiting Deep Neural Network Test Coverage from the Test Effectiveness Perspective. (CCF-B)**
Ming Yan, Junjie Chen*, Xuejie Cao, Zhuo Wu, Yuning Kang, Zan Wang.
In: Journal of Software: Evolution and Process, 2023, pages to appear.
4. [ICSE-SEIP'23] **Achieving Last-Mile Functional Coverage in Testing Chip Design Software Implementations. (CCF-A)**
Ming Yan, Junjie Chen*, Hangyu Mao, Jiajun Jiang, Jianye Hao, Xingjian Li, Zhao Tian, Zhichao Chen, Dong Li, Zhangkong Xian, Yanwei Guo, Wulong Liu, Bin Wang, Yuefeng Sun, Yongshun Cui.
In: The 45th International Conference on Software Engineering, SEIP track, May 14-20, 2023, pages to appear, Melbourne Convention and Exhibition Centre, Melbourne, Australia.

5. [ASE-NIER'22] **An Empirical Study on Numerical Bugs in Deep Learning Programs.**
 Gan Wang, Zan Wang, Junjie Chen*, Xiang Chen, Ming Yan.
In: The 37th IEEE/ACM International Conference on Automated Software Engineering, NIER track, October 10-14, 2022, pages to appear, Oakland Center, Michigan, USA
6. [FSE'21] **Exposing Numerical Bugs in Deep Learning via Gradient Back-propagation. (CCF-A)**
Ming Yan, Junjie Chen*, Xiangyu Zhang, Lin Tan, Gan Wang, Zan Wang.
In: The 29th ACM Joint European Software Engineering Conference and Symposium on the Foundations of Software Engineering, August 23-28, 2021, 627-638, Athens, Greece.
ACM SIGSOFT Distinguished Paper Award Nominee
7. [FSE'20] **Deep Learning Library Testing via Effective Model Generation. (CCF-A)**
 Zan Wang, Ming Yan†, Junjie Chen*, Shuang Liu, Dongdi Zhang.
In: The 28th ACM Joint European Software Engineering Conference and Symposium on the Foundations of Software Engineering, November 8-13, 2020, 788-799, Sacramento, California, United States.
 **ACM SIGSOFT Distinguished Paper Award**
8. [Journal of Software'20] **Survey on testing of deep neural networks. (CCF-B)**
 Zan Wang, Ming Yan†, Shuang Liu*, Junjie Chen, Dongdi Zhang, Zhuo Wu, Xiang Chen.
In: Journal of Software, 2020,31(5):1255–1275 (in Chinese).
9. [TOSEM'20] **Practical Accuracy Estimation for Efficient Deep Neural Network Testing.(CCF-A)**
 Junjie Chen, Zhuo Wu, Zan Wang, Hanmo You, Lingming Zhang, Ming Yan.
In: ACM Transactions on Software Engineering and Methodology (TOSEM),2020, 29(4): 1-35.,(Selected for ESEC/FSE 2021 Journal-First Presentation)

HONORS AND AWARDS

- Huawei Scholarship, Huawei - 2024
- Outstanding Ph.D Student Forum, CCF ChinaSoft - 2023
- Outstanding Contribution Award, Huawei & Tianjin University - 2023
- CIE Outstanding Master Dissertation Award, The Chinese Institute of Electronics - 2022
- Outstanding Graduate Student Award, Tianjin University (master' s degree) - 2021
- Outstanding Master Dissertation Award, Tianjin University - 2021
- National Scholarship, Ministry of Education - 2020
- Innovation Scholarship, College of Intelligence and Computing, Tianjin University - 2020
- ACM SIGSOFT Distinguished Paper Award - 2020
- Outstanding Graduate Student Awards, Tianjin University (bachelor' s degree) - 2018

VOLUNTEER EXPERIENCE

- **2024: ECOOP Artifact Evaluation Committee**
- **2023: ISSTA Artifact Evaluation Committee**
- 2024: ISSTA *co-reviewer*
- 2023: ESEC/FSE, ASE, ICSE (2024) *co-reviewer*
- 2022: ESEC/FSE, ASE *co-reviewer*
- 2021: ISSTA, TDSC *co-reviewer*
- 2020: ISSTA Tool Demo, JCST, COMPSAC, Journal of Software *co-reviewer*